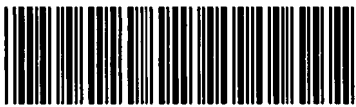


<b>Search Notes</b> 	<b>Application/Control No.</b> 10541994	<b>Applicant(s)/Patent Under Reexamination</b> HEIDE, PATRIC
	<b>Examiner</b> Chen, Shelley	<b>Art Unit</b> 3662

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
342	200	8/7/2007	SC

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
PALM (inventor, IDS)	5/12/2007	SC
EAST (see search history)	5/12/2007	SC
EAST (see search history)	8/7/2007	SC

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>